PCN Number:		20200730000.1A					ate:	Sep 10 2020	
Title:	Qualifica	ation of an	alternate	mount co	mpound for Select	Devices			
Custo	mer Conta	ct: PCN /	<u>Manager</u>	Dept:	Quality Services				
Proposed 1 st Shi		p Date:	Dec 8 2	020	Estimated Sample Date provided at				
					Ava	Availability: sample request			
	ge Type:	2		Docian		□ Wafe	r Rumi	o Sito	
Assembly Process			Design Data S	Wafer Bump Site Wafer Bump Material					
			_	umber change Wafer Bump Process					
Mechanical Specification			_	Test Site		Wafer Fab Site			
	acking/Ship			Test Pr	ocess	Wafe	r Fab I	Materials	
•					Wafe	Wafer Fab Process			
PCN Details									
Description of Change:									
				_					
				on of new	devices on page 2 a	above that	were r	not included on	
the on	ginal PCN n	otincation.							
This PCN is to inform of an alternative mount compound qualification for the devices in the product									
affected section as follows:									
			icernative	e mount co	ompound qualification	on for the	aevices	s in the product	
	ed section as	s follows:	Terriative	e mount co					
	ed section as	s follows: Vhat			Current		Additi	onal	
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affecte	ed section as	s follows: Vhat Compound			Current		Additi	onal	
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Qualification Results Data Displayed as: Number of lots / Total sample size / Total failed

Type	Test Name / Condition	Duration	Qual Device: CSD87503Q3ET
PC	Preconditioning	Level 1 @ 260C	3/462/0
TC	**Temperature Cycle, -65C/150C	500 Cycles	3/231/0
UHAST	**Unbiased HAST, 130C	96 Hours	3/231/0
MQ	Manufacturability (Assembly)	(per mfg. Site specification)	3/PASS
DS	Die Shear	QSS 009-009	3/30/0
WBP	Bond Pull	Wires	3/228/0
XRAY	X-ray	Devices	3/15/0
MSL	Moisture Sensitivity	Level 1 @ 260C	3/36/0

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1000 Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1000 Hours, and 170C/420 Hours
- The following are equivalent Temperature Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/ Green/Pb-free Status:

Qualified Pb-Free (SMT) and Green

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